

Measurement of the Non-linearity and Interpixel Capacitance of a H2RG Detector

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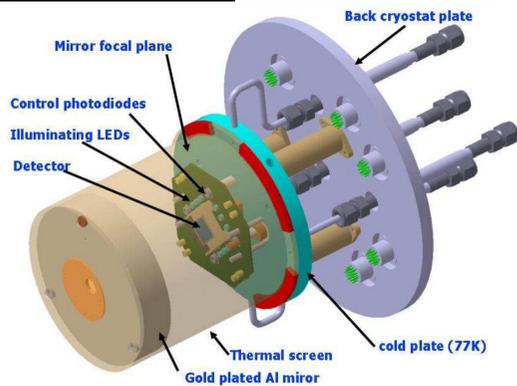
A temporal analysis of the noise of a H2RG detector is performed in view of the calibration of a dedicated setup. The implication on the noise performance of the subtraction of the reference output is described, and we extend the correlation method to groups of several pixels to derive the ratio χ of the interpixel capacitance to the pixel capacitance of a detector.

$$\text{We find } \chi = -0.0259 \pm 0.0017 \text{ (stat)} \pm 0.0020 \text{ (syst)}$$

All measurements are consistent to a sub-percent accuracy.



1. Setup and apparatus



To implement the detector tests described here, a dedicated cryostat was built in-house.

Cryostat specifications :

- Temperature range $100\text{K} < T < 160\text{K}$
- Temperature fluctuations $< 0.1\text{K}$ at equilibrium

Cryostat instrumentation :

- Several LED's around the detector
- Gold coated mirror allowing flat fields illumination
- Photodiodes to control flux and flat

The acquisition system is based on the architecture, where each sensor is connected to an Ethernet Network. The main component is the mezzanine board, which includes a 32 bit RISC microprocessor with a linux operating system. The generic design of the Mezzanine board allows its use in many different applications.

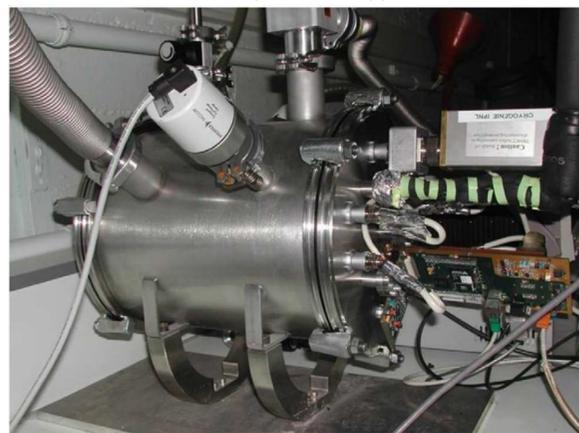
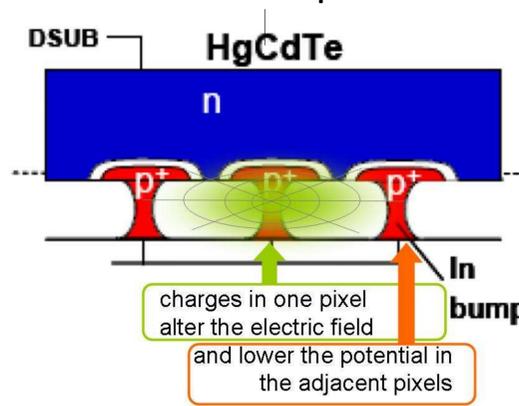


Fig. 2. Cryostat with the readout cards. The cryostat is cooled by liquid N2 from a 201 Dewar, providing an autonomy of 35h. LEDs inside the cryostat allow a uniform illumination for calibration purposes.

2. Calibration scheme

The method proposed here is a variant where the emphasis is on a redundant determination of the interpixel capacitance using groups of pixels, and a temporal analysis of the LED signal is performed, as would occur in an actual flux measurement. As the sensitivity of the result to common mode noise is an issue in correlation measurements, we compute the expected noise for groups of pixels, taking into account the presence of interpixel capacitance.

-> Influence Matrix between pixels



The charge in pixel i of a multipixel detector is also dependent on the voltage in pixel j , and the relation is given by the electrostatic influence matrix.

$$\Delta Q_i = C_{ij} \Delta V_j \text{ So that: } \delta V_j = (C)_{ij}^{-1} \delta Q_i$$

-> single pixel noise

Considering a pixel and its four neighbors, one can write C_{ij} as :

$$C_{ij} = C_0 \begin{pmatrix} 1 & x & x & x & x \\ x & 1 & 0 & 0 & 0 \\ x & 0 & 1 & 0 & 0 \\ x & 0 & 0 & 1 & 0 \\ x & 0 & 0 & 0 & 1 \end{pmatrix} \text{ Where } C_0 \text{ is the pixel capacitance, and } x = C_{ij}/C_{ii} = C_{ij}/C_0 \text{ is also called the interpixel capacitance.}$$

Considering that χ is small it is then possible to invert C_{ij} at the first order substituting χ by $-\chi$

Under a uniform illumination, all fluences are equal. The shot noise in pixel i can be derived from the Poisson fluctuation in the pixels and be written as :

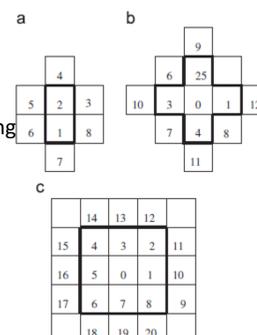
$$\langle (\delta_0)^2 \rangle = \frac{kq}{C_0(1-4x)} \Delta A_0 = s_1 \Delta A_0$$

A noise reduction is obtained when the reference output (which monitors the variations of the bias level) is subtracted, and the sensitivity to common mode noise is reduced. The 'up the ramp' readouts were split between several 'bursts' of 'frame' acquisitions performed at the clock frequency (100 kHz) and separated by an adjustable time. The number of frames in each burst varied between 60 and 15, depending on the illumination. The experimental results is shown on the variance versus fluence figure as the single pixel curve.

-> multi-pixel analysis

The previous formulae allow us to measure the ratio $\chi = C_{ij}/C_0$ by comparing the relation between noise and fluence for groups of pixels, as this changes the weight of the contribution of the neighbouring pixels.

The figure shows the contours of the pixels groups considered in this study.



The 2 pixels groups

A 8x8 capacitance matrix C should be considered and inverted exactly under the same assumptions as in the single pixel case (x small & first order only). The fluctuation for for pairs of pixels can then be found to be :

$$\langle (\delta_2)^2 \rangle = 2 \frac{kq}{C_0(1-4x)} (1-2x+4x^2) \Delta A_0$$

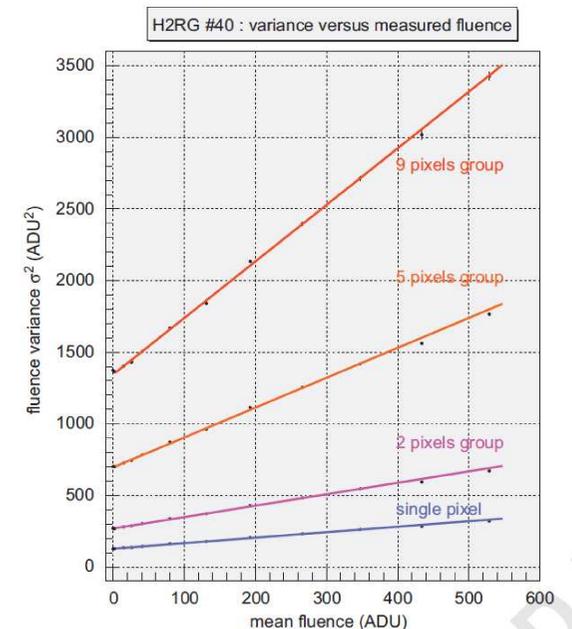
5 and 9 pixels groups

In the same way we find for the 5 and 9 pixels groups :

$$\langle (\delta_5)^2 \rangle = \left(\frac{kq}{C_0} \right) \frac{5-16x+40x^2}{1-4x} \Delta A_0$$

$$\langle \delta_9^2 \rangle = \frac{kq}{C_0} \frac{9-48x+80x^2}{1-4x} \Delta A_0$$

All the experimental measurements are reported on the figure below :



The three slopes ratio s_9/s_1 , s_5/s_1 and s_2/s_1 give us a redundant evaluation of x :

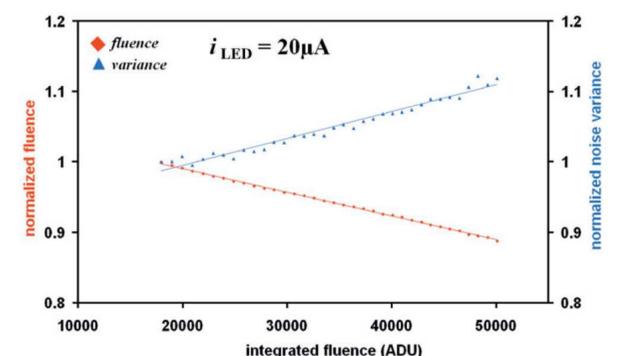
$$x = \frac{C_{int}}{C_0} = -0.0259 \pm 0.0017 \text{ (stat)} \pm 0.0020 \text{ (syst)}$$

The (single pixel) conversion factor can now be obtained as

$$f_1 = \frac{\Delta Q_0}{\Delta ADC_0} = \frac{1}{s_1(1-4x)^2} = 2.042 \text{ (e/ADU)}$$

3. Output FET non-linearities

We observe that the ADC level between 2 frames, proportional to $dADC/dt$, compared to the integrated ADC signal follow a proportional law. The fluence should be constant if the detector were linear. The slopes of the variance and of the fluence correspond to a similar and opposite relative variation.



A change of the transconductance of the output fet could account for such a variation: the slope of the variance (from the larger thermal noise) would then be correlated to the apparent decrease of the fluence with the same ADC level, as observed.

